

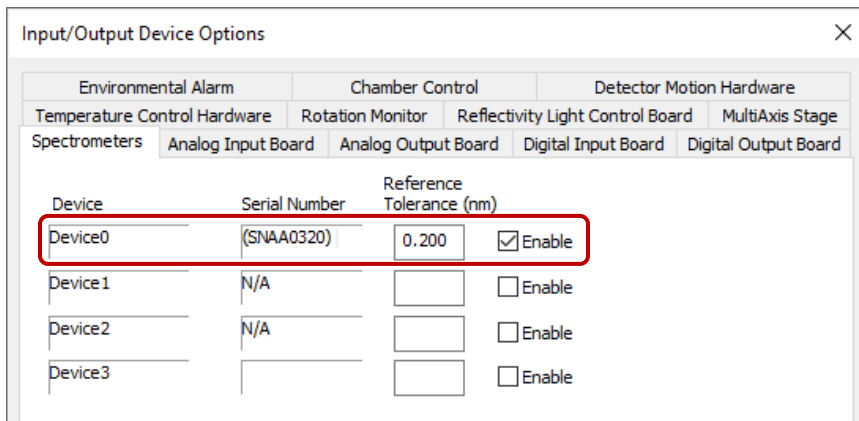
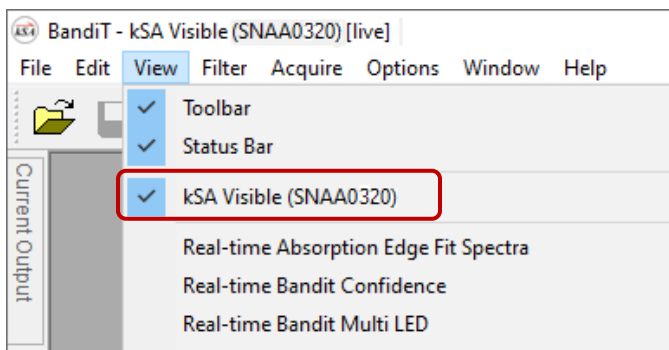


# Correcting Spectrometer Issues After Windows 10 Security Update

Sept. 23, 2020

On September 16, 2020, Microsoft released a security update that has affected many kSA BandiT users. This update caused Windows to remove the CDI driver, so kSA Bandit does not recognize the spectrometers.

When your kSA BandiT spectrometer is properly installed, it will be listed on the **View** menu and on the **Spectrometers** tab of the Options > Input/Output Device Options dialog.

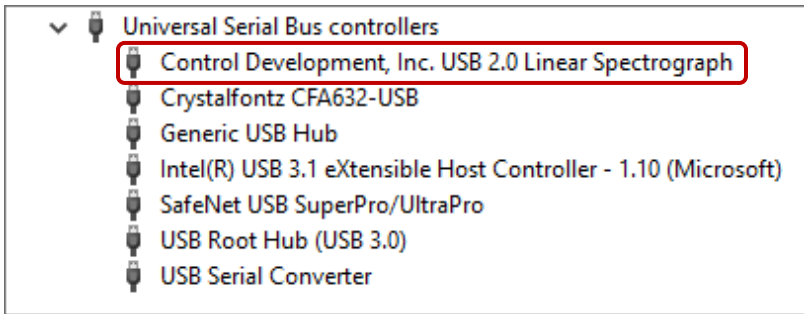




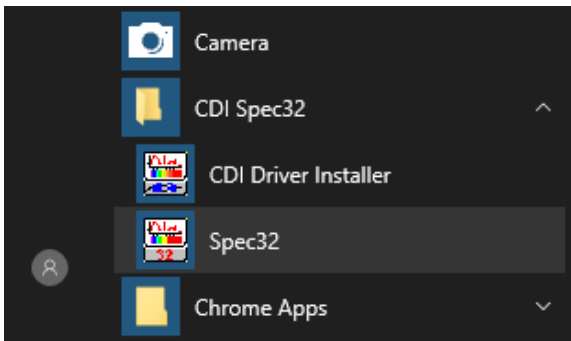
## Solution

If the spectrometer is not listed in your kSA BandiT application, follow these steps to correct the issue.

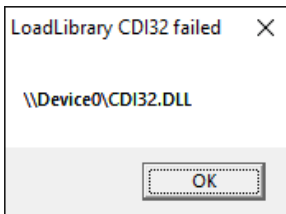
1. Open the Windows Device Manager and expand the **Universal Serial Bus controllers** item. The spectrometer will be listed as a “Control Development Spectrograph” or a similar name.



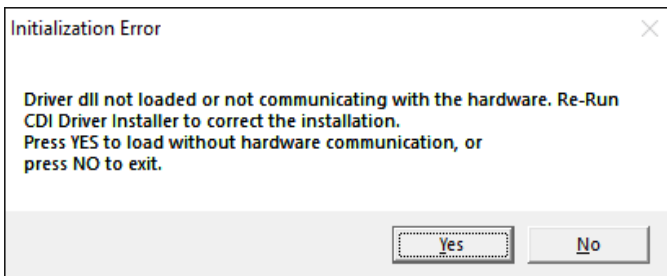
2. Try to run the **Spec32** application from the Windows Start menu.



3. If you receive the following error, click **OK**.



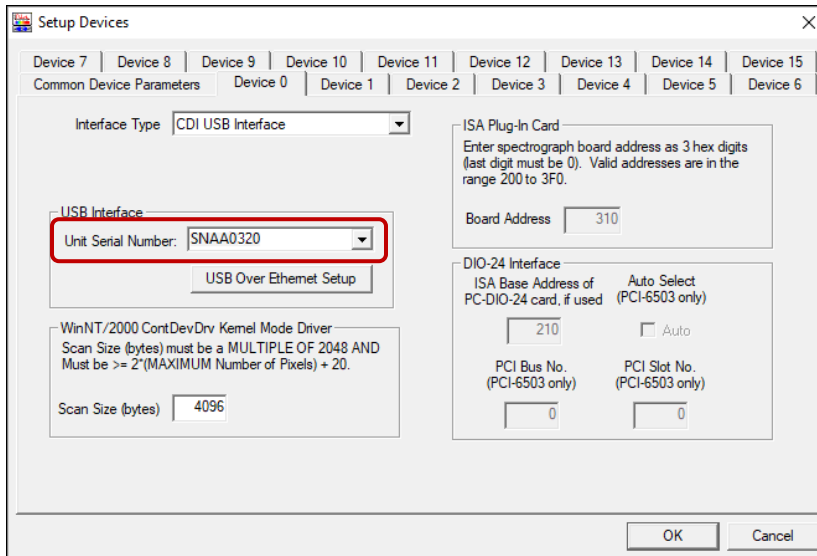
4. Click **OK** a the next error prompt.
5. At the Initialization Error prompt, click **No**.



6. Run the **CDI Driver Installer** from the Windows Start menu.



7. Click the **Device 0** tab, select your spectrometer in the **Unit Serial Number** field, and click **OK**.



8. If you receive a warning prompt asking you to reinstall a GUI element, click **Yes**.

Your spectrometer should now be available in the kSA BandiT software application.

#### **About k-Space Associates, Inc.**

*k-Space Associates, Inc., is a leading supplier to the semiconductor, surface science, and thin-film technology industries. Since 1992, we've delivered the most advanced thin-film characterization tools and software, thanks to close collaboration with our worldwide customer base. We realize the best products are developed with our customers' input, so we're good listeners. For your real-time surface analysis, curvature/stress, temperature, deposition rate, or custom project, we look forward to helping you with your thin-film characterization needs.*